

Application/Control No.	Applicant(s)/Patent under Reexamination
10/816,756	CHAN ET AL.
Examiner	Art Unit
Matthew Heneghan	2134

	SEARCHED				
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST, keyword+citation search, see notes	9/2/2007	MH	
ACM keyword search, see notes	9/3/2007	мн	
Inventor Search	9/3/2007	МН	